## Notice of References Cited

40/572 526	Applicant(s)/Pater Reexamination LEE ET AL.	nt Under
Examiner	Art Unit	
GREG BENGZON	2444	Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0220926 A1	11-2004	Lamkin et al.	707/003
*	В	US-2004/0220791 A1	11-2004	Lamkin et al.	703/011
*	С	US-2003/0229900 A1	12-2003	Reisman, Richard	725/87
*	D	US-2005/0267994 A1	12-2005	Wong et al.	709/246
*	Е	US-2002/0143901 A1	10-2002	Lupo et al.	709/219
*	F	US-7,434,247 B2	10-2008	Dudkiewicz et al.	725/46
*	G	US-7,055,168 B1	05-2006	Errico et al.	725/46
*	Н	US-2003/0061610 A1	03-2003	Errico, James H.	725/46
*	Т	US-2008/0028101 A1	01-2008	Dewa, Yoshiharu	709/246
*	J	US-7,359,955 B2	04-2008	Menon et al.	709/219
*	к	US-2004/0267805 A1	12-2004	Sezan et al.	707/102
	L	US-			
	м	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	ø					
	R					
	s					
	Т					

## NON DATENT DOCUMENTS

*	* Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
	U		
	v		
	w		
	x		

"A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.